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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 7

### Complete if Known

Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	<del>Unknown</del> JACK DINH
Attorney Docket Number	402801

Examiner Initials *	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
JD	1	2,959,105		Sayanagi	11-08-1980	
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	3	3,305,294		Alvarez	02-21-1967	
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Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DIAZ
Attorney Docket Number	402801

### U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
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Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

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Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sub>6</sub>
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				
JD	1	EPO	0759573 A2		Eastman Kodak Company	02-26-1997		
	2	EPO	0531926 B1		Matsushita Electric Industrial Co., Ltd.	3-17-1993		
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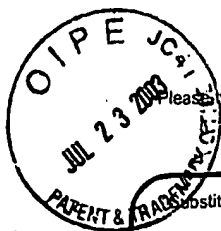
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Sheet 4 of 7

### Complete if Known

Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

### OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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Sheet 5 of 7

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Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
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### OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

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Substitute for form 1449A/PTO		<b>Complete if Known</b>			
		Application Number	09/942,392		
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		Filing Date	31 August 2001		
		First Named Inventor	Edward Raymond Dowski, Jr.		
		Group Art Unit	2873		
		Examiner Name	Unknown JACK DINH		
Sheet	7	of	7	Attorney Docket Number	402801

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. 1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	48	Abstract of JP 60247611 A, published 12 July 1985 (Toshiba KK), Patent Abstracts of Japan, 6 May 1986, vol. 010, no. 119 (p-435), 1 page	
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